

<b>Notice of References Cited</b>	Application/Control No. 10/536,553		Applicant(s)/Patent Under Reexamination VAN DEIJZEN, WILHELMUS P	
	Examiner CHIKAODILI E. ANYIKIRE		Art Unit 2482	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,926,103 A	07-1999	Petite, T. David	340/825.19
*	B	US-5,956,081 A	09-1999	Katz et al.	348/163
*	C	US-6,243,483 B1	06-2001	Petrou et al.	382/103
*	D	US-6,438,696 B1	08-2002	Baran et al.	726/22
*	E	US-6,504,479 B1	01-2003	Lemons et al.	340/541
*	F	US-6,611,206 B2	08-2003	Eshelman et al.	340/573.1
*	G	US-2004/0101166 A1	05-2004	Williams et al.	382/104
*	H	US-2004/0158869 A1	08-2004	Safran et al.	725/105
*	I	US-6,633,232	10-2003	Trajkovic et al.	340/573.1
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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